

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 244085US2		SERIAL NO. NEW APPLICATION	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Yukinori HIROSE			
				FILING DATE HEREWITH		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	AA	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>W</i>	AO	2000-321224	11/24/00	Japan (with English Abstract)			X
	AP	2810370	07/31/98	Japan (with English Translation of Claim 1 and Advantageous Effect of the Invention)			X
	AQ	2002-5857	01/09/02	Japan (with English Abstract)			X
	AR	9-274883	10/21/97	Japan (with English Abstract)			X
<i>W</i>	AS	8-115699	05/07/96	Japan (with English Translation of Claim 1 and Advantageous Effect of the Invention)			X
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>W</i>	AW	Seiichi SUZUKI, "Introduction to EBSP Method and its Advantages with Nano Probe Schottky FE-SEM", Materia Japan, Vol. 40, No. 7, March 22, 2001, pp. 612-616 (With English Extract)					
<i>W</i>	AX	Seiichi SUZUKI, "Crystal Structure Microanalysis of Metal Surface Using EBSP Method", IDEMA Japan News, No. 38, pp. 8-14 (with English Extract)					
	AY						
	AZ						
Examiner <i>[Signature]</i>					<input type="checkbox"/> Additional References sheet(s) attached Date Considered <i>7/16/01</i>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							